



Ultra Fast NPT - IGBT® with Ultra Soft Recovery Diode

The Ultra Fast 650V NPT-IGBT® family of products is the newest generation of IGBTs optimized for outstanding ruggedness and best trade-off between conduction and switching losses.

Features

- Low Saturation Voltage
- Low Tail Current
- RoHS Compliant
- Smooth Reverse Recovery
- Short Circuit Withstand Rated
- High Frequency Switching
- Ultra Low Leakage Current
- · Snap-free Switching



Combi (IGBT and Diode)



Unless stated otherwise, Microsemi discrete IGBTs contain a single IGBT die. This device is recommended for applications such as induction heating (IH), motor control, general purpose inverters and uninterruptible power supplies (UPS).

MAXIMUM RATINGS

All Ratings:	$I_C = 25^{\circ}C$	unless	otherwise	specified.
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Symbol	Parameter	Ratings	Unit
V _{ces}	Collector Emitter Voltage	650	V
V_{GE}	Gate-Emitter Voltage	±30	V
I _{C1}	Continuous Collector Current @ T _c = 25°C	134	
I _{C2}	Continuous Collector Current @ T _c = 110°C	65	Α
I _{CM}	Pulsed Collector Current ①	280	
SCWT	Short Circuit Withstand Time: V _{CE} = 600V, V _{GE} = 15V, T _C =125°C	10	μs
P _D	Total Power Dissipation @ T _c = 25°C	595	W
T_{J},T_{STG}	Operating and Storage Junction Temperature Range	-55 to 150	ى ئ
T_{L}	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300	C

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Min	Тур	Max	Unit
V _{(BR)CES}	Collector-Emitter Breakdown Voltage (V _{GE} = 0V, I _C = 350µA)	650			
V _{GE(TH)}	Gate Threshold Voltage $(V_{CE} = V_{GE}, I_{C} = 1.0 \text{mA}, T_{j} = 25 ^{\circ}\text{C})$	3.5	5.0	6.5	
V _{CE(ON)}	Collector-Emitter On Voltage $(V_{GE} = 15V, I_C = 70A, T_j = 25^{\circ}C)$		1.9	2.4	Volts
	Collector-Emitter On Voltage (V _{GE} = 15V, I _C = 70A, T _j = 125°C)		2.4		
	Collector-Emitter On Voltage (V _{GE} = 15V, I _C = 140A, T _j = 25°C)		2.6		
	Collector Cut-off Current (V _{CE} = 650V, V _{GE} = 0V, T _j = 25°C) ②		20	350	
CES	Collector Cut-off Current (V _{CE} = 650V, V _{GE} = 0V, T _j = 125°C) ②		200		μΑ
I _{GES}	Gate-Emitter Leakage Current (V _{GE} = ±20V)			±250	nA

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C _{ies}	Input Capacitance	Capacitance		4250		
C _{oes}	Output Capacitance	$V_{GE} = 0V, V_{CE} = 25V$		847		pF
C _{res}	Reverse Transfer Capacitance	f = 1MHz		415		
V_{GEP}	Gate to Emitter Plateau Voltage	Gate Charge		7.0		V
Q ³	Total Gate Charge	V _{GE} = 15V		226	305	
Q_{ge}	Gate-Emitter Charge	V _{CE} = 325V		26	35	nC
Q_{gc}	Gate- Collector Charge	I _C = 70A		104	140	
t _{d(on)}	Turn-On Delay Time	Inductive Switching (25°C)		18		
t,	Current Rise Time	V _{cc} = 433V		49		20
t _{d(off)}	Turn-Off Delay Time	V _{GE} = 15V		170		ns
t _f	Current Fall Time	I _C = 70A		67		
E _{on2} ⑤	Turn-On Switching Energy	$R_{\rm g} = 4.3\Omega^{(4)}$		1868	2800	1
E _{off}	Turn-Off Switching Energy	T _J = +25°C		1470	2205	μJ
t _{d(on)}	Turn-On Delay Time	Inductive Switching (125°C)		17		
t,	Current Rise Time	V _{cc} = 433V		51		20
$t_{d(off)}$	Turn-Off Delay Time	V _{GE} = 15V		190		ns
t _f	Current Fall Time	I _C = 70A		74		
E _{on2} 5	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3\Omega^{(4)}$		2616	3920	1
E _{off}	Turn-Off Switching Energy	T _J = +125°C		1900	2865	μJ

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	Min	Тур	Max	Unit
$R_{_{ heta JC}}$	Junction to Case Thermal Resistance (IGBT)			0.21	°C/W
	Junction to Case Thermal Resistance (Diode)			0.61	
R _{eJA}	Junction to Ambient Thermal Resistance			40	
10/	Package Weight		0.22		oz
$W_{\scriptscriptstyle T}$			6.2		g

- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- 2 Pulse test: Pulse Width < 380 μ s, duty cycle < 2%.
- 3 See Mil-Std-750 Method 3471.
- 4 R_c is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)
- 5 E_{on2} is the energy loss at turn-on and includes the charge stored in the freewheeling diode.
- 6 E_{off} is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

TYPICAL PERFORMANCE CURVES

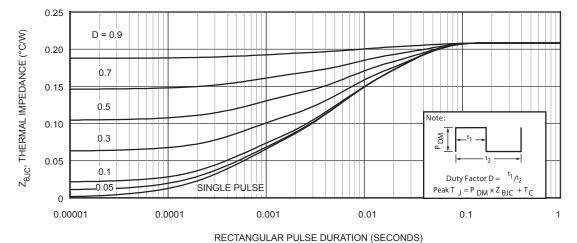
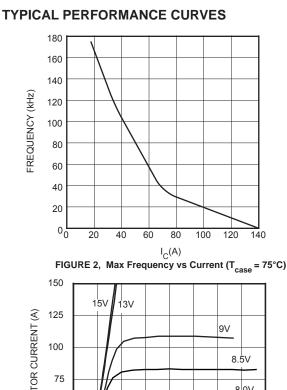
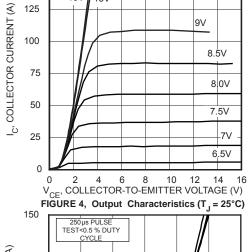
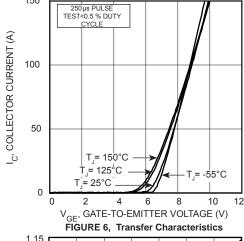


Figure 1, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration







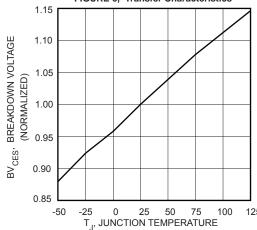
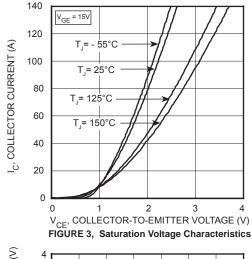


FIGURE 8, Breakdown Voltage vs Junction Temperature



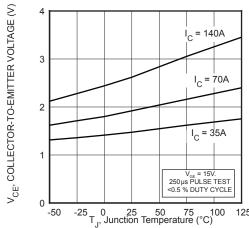


FIGURE 5, On State Voltage vs Junction Temperature $V_{CE'}$ COLLECTOR-TO-EMITTER VOLTAGE (V) 250µs PULSE TEST <0.5 % DUTY CYCLE 3 I_C = 140A 2 $I_{C} = 35A$ 12

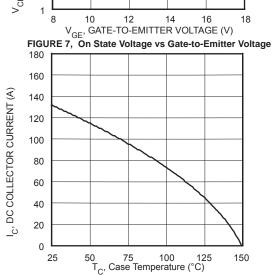
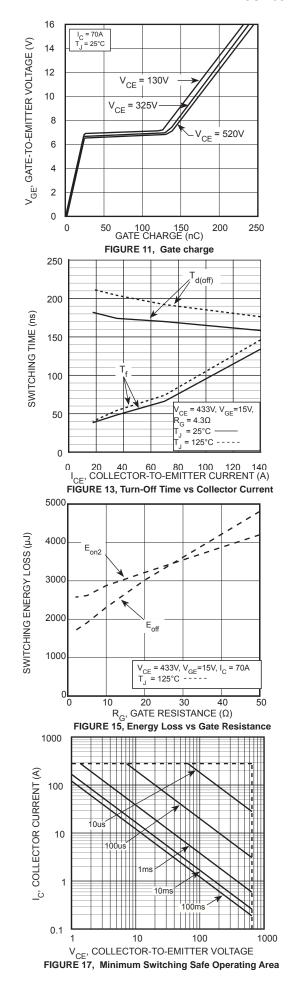


FIGURE 9, DC Collector Current vs Case Temperature

FIGURE 16, Swiitching Energy vs Junction Temperature



ULTRA SOFT RECOVERY ANTI-PARALLEL DIODE

MAXIMUM RATINGS

Symbol	Characteristic / Test Conditions		Ratings	Unit
I _F Maximum D.C. Forward Current	Maximum D.C. Fanuard Current	T _C = 25°C	57	
	T _c = 75°C	40	Amps	
I _{FSM}	Non-Repetitive Forward Surge Current ($T_J = 25^{\circ}$ C, $t_p = 10$ ms, Half Sine)		210	

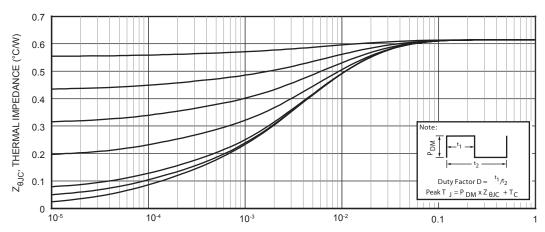
STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions		Min	Тур	Max	Unit
		I _F = 40A		3.0		
V_{F}	Forward Voltage	I _F = 80A		3.9		Volts
		I _F = 40A, T _J = 125°C		2.3		

DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
t _{rr}	Reverse Recovery Time	$I_F = 1.0A$, dif/dt= -100 A/ μ s, $V_R = 30V$, $T_j = 25$ °C		25		ns
t _{rr}	Reverse Recovery Time	I ₌ = 40 Amps		75		ns
Q _{rr}	Reverse Recovery Charge	dif/dt= -200 A/µs		111		nC
I	Maximum Reverse Recovery Current	V _R = 433 Volts		4		Amps
E _{rr}	Reverse Recovery Energy	T _j = 25°C		2		μJ
t _{rr}	Reverse Recovery	$I_F = 40 \text{ Amps}$ dif/dt = -200 A/µs $V_R = 433 \text{ Volts}$ $T_j = 125^{\circ}\text{C}$		362		ns
Q _{rr}	Reverse Recovery Charge			1062		nC
I _{rrm}	Maximum Reverse Recovery Current			8		Amps
E _{rr}	Reverse Recovery Energy			83		μJ
t _{rr}	Reverse Recovery	I ₌ = 40 Amps		160		ns
Q _{rr}	Reverse Recovery Charge	dif/dt= -1000 A/µs V _R = 433 Volts T _j = 125°C		1648		nC
I _{rrm}	Maximum Reverse Recovery Current			25		Amps
E _{rr}	Reverse Recovery Energy			261		μJ
S	Softness Factor (tb/ta)	$I_F = 20A$, dif/dt= -1000 A/µs, $V_R = 433V$, $T_j = 125$ °C		3		

TYPICAL PERFORMANCE CURVES



RECTANGULAR PULSE DURATION (seconds)
FIGURE 18. MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION-TO-CASE vs. PULSE DURATION

TYPICAL PERFORMANCE CURVES

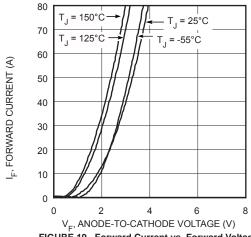


FIGURE 19, Forward Current vs. Forward Voltage

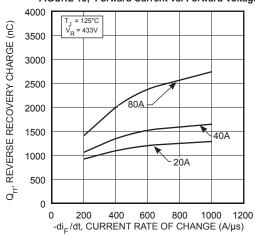


Figure 21. Reverse Recovery Charge vs. Current Rate of Change

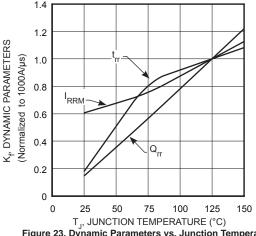


Figure 23. Dynamic Parameters vs. Junction Temperature

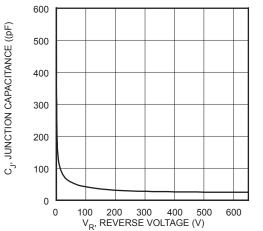


Figure 25. Junction Capacitance vs. Reverse Voltage

APT70GR65B2DU40

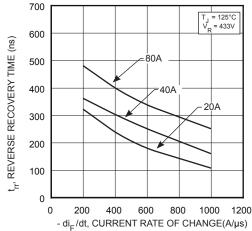


Figure 20. Reverse Recovery Time vs. Current Rate of Change

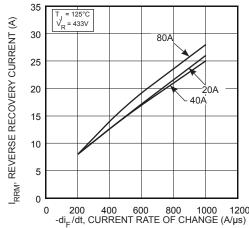


Figure 22. Reverse Recovery Current vs. Current Rate of Change

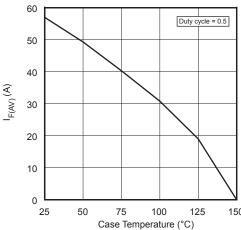


Figure 24. Max Average Forward Current vs. CaseTemperature

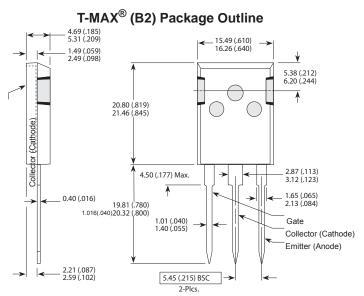
0.25 I_{RRM}

Zero

Figure 26. Diode Test Circuit

- I_F Forward Conduction Current
- 2 di₋/dt Rate of Diode Current Change Through Zero Crossing.
- 3 I_{RRM} Maximum Reverse Recovery Current
- f 4 t_a Time to reach Maximum Reverse Recovery Current (I_{RRM}).
- $_{\rm b}$ Time from Maximum Reverse Recovery Current ($I_{\rm RRM}$) to projected zero crossing based on a straight line from $I_{\rm RRM}$ through 25% $I_{\rm RRM}$.
- 6 t_{rr} Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25, I_{RRM} passes through zero.
- \mathbf{Q}_{rr} Area Under the Curve Defined by \mathbf{I}_{RRM} and \mathbf{t}_{RR}

Figure 27. Diode Reverse Recovery Waveform Definition



These dimensions are equal to the TO-247 without the mounting hole.

Dimensions in Millimeters and (Inches)

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 NGTG40N120FL2WG

 RJH60F3DPQ-A0#T0
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 APT15GT120BRG
 APT20GT60BRG
 NGTB75N65FL2WAG
 NGTG15N120FL2WG

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 IXA40RG1200DHGLB
 APT70GR65B2DU40
 NTE3320
 QP12W05S-37A
 IHFW40N65R5SXKSA1
 APT70GR120J

 APT35GP120JDQ2
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